

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS2434	Feb-96	9537 C4	CARSEM	DM512002AAD	1.2μ OX/NI	03 PR-35

STRESS/JOB NO.

READPOINT (Sample Size/No. of Fails)

Infant / High voltage Life 125°C, 7.0 V. P-16958, P-17018	<u>48 Hr</u> 231/1 F1	<u>336 Hr</u> 77/0	<u>1KHr</u> 77/3 F2	<u>*Failure Rate</u> 175 Fits
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*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-17019	<u>300 ~</u> 38/0	<u>1K ~</u> 38/1 F3	<u>Cum %</u> 2.6%
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Biased Moisture (HAST) 120°C/85% RH, 5.5 V. P-17020	<u>100 Hr</u> 77/0	<u>Cum %</u> 0.0%
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Autoclave 121°C/100% RH, 2 Atmos P-17021	<u>96 Hr</u> 38/0	<u>Cum %</u> 0.0%
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Failure Mode

- F1: Icc Stdby
- F2: 3-Icc Stdby
- F3: Continuity